

TestForum 2019

Sokos Hotel Viru, Tallinn, Estonia

Tuesday, November 26th, 2019

Time	Titles	Speakers or additional info
08:30-08:50	Registration	
08:50-09:00	Welcome / Introduction	Knut Båstoløkken
09:00-10:00	Key Note Session	<i>Chairman: Knut Båstoløkken</i>
09:00-10:00	Ericsson Estonia Journey to Intelligent Manufacturing and Augmented Reality Troubleshooting	Welix Klaas, Ericsson Eesti AS
10:00-10:30	Exhibitor Forum: short presentations	<i>Chairman: Mick Austin</i>
10:30-11:00	Coffee Break / Exhibition	
11:00-12:30	Session 1: Test Strategies, reliability, structural test	<i>Chairman: Stig-Gunnar Jensen</i>
11:00-11:30	In search for the right way of production testing	Lauri Anttila, Planmeca Oy
11:30-12:00	Can NZT be used as tool to find Shorts?	Lothar Diez, SPEA
12:00-12:30	Mitigating JTAG as an Attack Surface	Reg Waller , ASSET InterTech
12:30-13:30	Lunch	
13:30-15:00	Session 2: Structural Test	<i>Chairman: Mattias Ericsson</i>
13:30-14:00	New ICT technology	Frank Grossmann, ATEip
14:00-14:30	Total Solutions of TRI's Automated X-ray Inspection	Anthony Wang, TRI
14:30-15:00	Top test coverage will only be achieved in combination with AXI	Andreas Türk, GÖPEL electronic
15:00-15:30	Coffee Break / Exhibition	
15:30-16:30	Session 3: Test Automation	<i>Chairman: Magnus Rönqvist</i>
15:30-16:00	In-line RF Electronics Testing Challenges	Ramon Llavall, 6TL
16:00-16:30	Smart Electronic Factory – How Autonomous Intelligent Vehicles change it to a Smart CONNECTED Electronic Factory	Mr. Alfred Pammer, CTS, Germany
16:30-17:00	News from conferences	<i>Chairman: Artur Jutman</i>
17:00-17:30	Fruit & Refreshments / Exhibition	
17:30-19:00	Panel debate: "Should a test remain stable through lifetime of a product – or adapt to realities?"	<i>Panel moderator: Birger Schneider</i>
19:30	Dinner	

Wednesday, November 27th, 2019

Time	Titles	Speakers or additional info
09:00-10:30	Session 4: Functional test, fixturing and test interfaces	<i>Chairman: Mats Klarholm</i>
09:00-09:30	Simple DIY functional tester	Artur Jutman, Testonica Lab
09:30-10:00	Maximising Functional Test Fixture Performance by Eliminating Cables	Gary Clayton, MacPanel
10:00-10:30	Contact technologies for high reliable repetitive testing	Mads Haastrup, ODU
10:30-11:00	Coffee Break / Exhibition	
11:00-12:30	Session 5: JTAG Based Test	<i>Chairman: Paulius Musteikis</i>
11:00-11:30	Emulation based Boundary Scan tests	Jan Heiber, GÖPEL
11:30-12:00	Functional port for accessing on-chip instruments	Erik Larsson, Lund University
12:00-12:30	Case study –Testing a PCBA with BGAs using boundary scan and JFT	Lauri Anttila, Planmeca Oy
12:30-13:30	Lunch	
13:30-15:00	Session 6: Mixed session	<i>Chairman: Lars Kongsted-Jensen</i>
13:30-14:00	Thermal design and subsequent temperature stressing – a challenge for LED lighting and power electronics	Birger Schneider, Chamaj
14:00-14:30	Embedded FPGA-based Test for BGAs Power/Ground Solder Joints	Sergei Odintsov, TalTech
14:30-15:00	New Flashing methods	Samuele Stefanoni, SMH Technologies
15:00-15:10	Closing Session: TestForum concluding remarks	<i>Knut Båstoløkken Kitron</i>